

INTERNATIONAL STANDARD



GROUP SAFETY PUBLICATION

**Safety requirements for electrical equipment for measurement, control, and laboratory use –
Part 031: Safety requirements for hand-held and hand-manipulated probe assemblies for electrical test and measurement**



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**Safety requirements for electrical equipment for measurement, control, and laboratory use –
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CONTENTS

FOREWORD	7
1 Scope and object	10
2 Normative references	10
3 Terms and definitions	11
3.1 Parts and accessories	11
3.2 Quantities	12
3.3 Tests	13
3.4 Safety terms	13
3.5 Insulation	14
4 General	15
4.1 Type of probe assemblies	15
4.2 Object Safety aspects	22
4.2.1 Aspects included in scope Identified HAZARDS	22
4.2.2 Aspects excluded from scope	22
4.3 Verification	23
4.4 Environmental conditions	23
4.4.1 Normal environmental conditions	23
4.4.2 Extended environmental conditions	23
5 Tests	23
5.1 General	23
5.2 Sequence of tests	24
5.3 Reference test conditions	24
5.3.1 Environmental conditions	24
5.3.2 State of probe assemblies	24
5.3.3 Position of the probe assembly	24
5.3.4 Accessories	25
5.3.5 Covers and removable parts	25
5.3.6 Input and output voltages	25
5.3.7 Controls	25
5.3.8 Connections	25
5.3.9 Short-term or intermittent operation	25
5.4 Testing in SINGLE FAULT CONDITION	25
5.4.1 General	25
5.4.2 Application of fault conditions	25
5.4.3 Duration of tests	26
5.4.4 Conformity after application of fault conditions	26
5.5 Tests in REASONABLY FORESEEABLE MISUSE	27
5.5.1 General	27
5.5.2 Fuses	27
6 Marking and documentation	27
6.1 Marking	27
6.1.1 General	27
6.1.2 Identification	28
6.1.3 Fuses	29
6.1.4 CONNECTORS and operating devices	29
6.1.5 RATING	29

6.2	Warning markings.....	29
6.3	Durability of markings	30
6.4	Documentation	30
6.4.1	General.....	30
6.4.2	Probe assembly RATING	30
6.4.3	Probe assembly operation	30
6.4.4	Probe assembly maintenance and service	31
7	Protection against electric shock	32
7.1	General.....	32
7.2	Determination of ACCESSIBLE parts.....	32
7.2.1	General.....	32
7.2.2	Examination	32
7.2.3	Openings for pre-set controls.....	34
7.3	Limit values for ACCESSIBLE parts	34
7.3.1	General.....	34
7.3.2	Levels in NORMAL CONDITION	35
7.3.3	Levels in SINGLE FAULT CONDITION	35
7.3.4	Measurement of voltage and touch current.....	37
7.4	Means of protection against electric shock	40
7.4.1	General.....	40
7.4.2	CONNECTORS	41
7.4.3	PROBE TIPS	43
7.4.4	Impedance	47
7.4.5	PROTECTIVE IMPEDANCE	47
7.4.6	BASIC INSULATION, SUPPLEMENTARY INSULATION, DOUBLE INSULATION and REINFORCED INSULATION	47
7.5	Insulation requirements.....	48
7.5.1	The nature of insulation	48
7.5.3	CREEPAGE DISTANCES	54
7.5.4	Solid insulation for probe assemblies	56
7.6	Procedure for voltage tests	63
7.6.1	General.....	63
7.6.2	Humidity preconditioning.....	63
7.6.3	Conduct of tests	64
7.6.4	Test voltages.....	64
7.6.5	Test procedures	66
7.7	Constructional requirements for protection against electric shock.....	67
7.7.1	General.....	67
7.7.2	Insulating materials	67
7.7.3	ENCLOSURES of probe assemblies with DOUBLE INSULATION or REINFORCED INSULATION	67
7.7.4	PROBE WIRE attachment	68
8	Protection against mechanical HAZARDS	71
9	Resistance to mechanical stresses	71
9.1	General.....	71
9.2	Rigidity test	72
9.3	Drop test.....	72
9.4	Impact swing test.....	72
10	Temperature limits and protection against the spread of fire	73

9.1	General	74
9.2	Temperature tests	75
10	Resistance to heat	75
10.1	Integrity of SPACINGS	75
10.2	Resistance to heat	75
11	Protection against HAZARDS from fluids	74
11.1	Cleaning	75
11.2	Specially protected probe assemblies	75
12	Components	75
12.1	General	75
12.2	Fuses	76
12.3	PROBE WIRE	76
12.3.1	General	76
12.3.2	RATING of PROBE WIRE	76
12.3.3	Pressure test at high temperature for insulations	77
12.3.4	Tests for resistance of insulation to cracking	78
12.3.5	Voltage test	79
12.3.6	Tensile test	79
13	Prevention of HAZARD from arc flash and short-circuits	81
13.1	General	81
13.2	Exposed conductive parts	81
Annex A (normative)	Measuring circuits for touch current (see 7.3)	83
A.1	Measuring circuits for AC with frequencies up to 1 MHz and for DC	83
A.2	Measuring circuits for AC with sinusoidal frequencies up to 100 Hz and for DC	83
A.3	Current measuring circuit for electrical burns at frequencies above 100 kHz	84
A.4	Current measuring circuit for WET LOCATIONS	85
Annex B (normative)	Standard test fingers	87
Annex C (normative)	Measurement of CLEARANCES and CREEPAGE DISTANCES	90
Annex D (normative)	Routine spark tests on PROBE WIRE	92
D.1	General	92
D.2	Spark test procedure	92
D.3	Routine spark test method for PROBE WIRE	94
Annex E (informative)	4 mm CONNECTORS	96
E.1	General	96
E.2	Dimensions	96
Annex F (normative)	MEASUREMENT CATEGORIES	98
F.1	General	98
F.2	MEASUREMENT CATEGORIES	98
F.2.1	MEASUREMENT CATEGORY II	98
F.2.2	MEASUREMENT CATEGORY III	98
F.2.3	MEASUREMENT CATEGORY IV	98
F.2.4	Probe assemblies without a MEASUREMENT CATEGORY RATING	99
Annex G (informative)	Determination of CLEARANCES for Table 2	102
Annex H (informative)	Line-to-neutral voltages for common mains supply systems	103
Annex I (informative)	Index of defined terms	105
Bibliography		107

List of comments.....	109
Figure 1 – Example of a STACKABLE CONNECTOR with a male CONNECTOR and a female TERMINAL.....	12
Figure 2 – Examples of Type A probe assemblies	16
Figure 3 – Examples of type C probe assemblies	16
Figure 3 – Example of Type B probe assemblies	18
Figure 4 – Examples of Type D probe assemblies	21
Figure 5 – Examples of Type E probe assemblies	21
Figure 6 – Examples of Type F probe assemblies.....	22
Figure 7 – Methods for determination of ACCESSIBLE parts (see 6.2) and for voltage tests of (see 6.4.2)	34
Figure 8 – Capacitance level versus voltage in NORMAL CONDITION and SINGLE FAULT CONDITION (see 7.3.2 c) and 7.3.3 c))	36
Figure 9 – Voltage and touch current measurement.....	37
Figure 10 – Voltage and touch current measurement for the REFERENCE CONNECTOR	38
Figure 11 – Voltage and touch current measurement with shielded test probe	39
Figure 12 – Maximum test probe input voltage for 70 mA touch current.....	40
Figure 13 – Protection by a PROTECTIVE FINGERGUARD.....	44
Figure 14 – Protection by distance.....	45
Figure 15 – Protection by tactile indicator	46
Figure 16 – Example of probe assembly with IP2X PROBE TIP.....	46
Figure 17 – Example of recurring peak voltage.....	53
Figure 18 – Distance between conductors on an interface between two layers	58
Figure 19 – Distance between adjacent conductors along an interface of two layers.....	59
Figure 20 – Distance between adjacent conductors located between the same two layers	61
Figure 21 – Flexing test.....	69
Figure 22 – Rotational flexing test	71
Figure 23 – Impact swing test.....	73
Figure 24 – Indentation device.....	77
Figure A.1 – Measuring circuit for AC with frequencies up to 1 MHz and for DC	83
Figure A.2 – Measuring circuits for AC with sinusoidal frequencies up to 100 Hz and for DC.....	84
Figure A.3 – Current measuring circuit for electrical burns.....	85
Figure A.4 – Current measuring circuit for high frequency test probes.....	85
Figure A.5 – Current measuring circuit for WET LOCATIONS.....	86
Figure B.1 – Rigid test finger	87
Figure B.2 – Jointed test finger.....	88
Figure D.1 – Bead chain configuration (if applicable).....	93
Figure E.1 – Recommended dimensions of 4 mm CONNECTORS	97
Figure F.1 – Example to identify the locations of MEASUREMENT CATEGORIES	100
Table 1 – Symbols	28

~~Table 2 – SPACINGS for unmated CONNECTORS RATED up to 1 000 V a.c. or 1 500 V d.c. with HAZARDOUS LIVE conductive parts~~

Table 2 – CLEARANCES for unmated CONNECTORS	43
Table 3 – Multiplication factors for CLEARANCES of probe assembly RATED for operation at altitudes up to 5 000 m	49
Table 4 – CLEARANCES for probe assemblies RATED for MEASUREMENT CATEGORIES	49
Table 5 – CLEARANCE values for the calculation of 7.5.2.3.2	52
Table 6 – CLEARANCES for BASIC INSULATION in probe assemblies subjected to recurring peak voltages or WORKING VOLTAGES with frequencies above 30 kHz	54
Table 7 – CREEPAGE DISTANCES for BASIC INSULATION or SUPPLEMENTARY INSULATION	54
Table 8 – Impulse test voltages for testing electric strength of solid insulation for probe assemblies RATED for MEASUREMENT CATEGORIES	57
Table 9 – AC test voltages for testing electric strength of solid insulation for probe assemblies RATED for MEASUREMENT CATEGORIES	57
Table 10 – Minimum values for distance or thickness of solid insulation for probe assemblies RATED for MEASUREMENT CATEGORIES	59
Table 11 – Test voltages based on CLEARANCES	65
Table 12 – Correction factors according to test site altitude for test voltages for CLEARANCES	66
Table 13 – Pull forces for PROBE WIRE attachment tests	70
Table 14 – Surface temperature limits in NORMAL CONDITION	73
Table 15 – Diameter of mandrel and numbers of turns	78
Table C.1 – Dimension of X	90
Table C.2 – Methods of measuring CLEARANCES and CREEPAGE DISTANCES	90
Table D.1 – Maximum centre-to-centre spacings of bead chains	92
Table D.2 – Formula for maximum speed of wire in terms of electrode length L of link- or bead-chain electrode	94
Table F.1 – Characteristics of MEASUREMENT CATEGORIES	101
Table G.1 – CLEARANCES values for Table 2	102
Table H.1 – Line-to-neutral voltages for common mains supply systems	104

INTERNATIONAL ELECTROTECHNICAL COMMISSION

SAFETY REQUIREMENTS FOR ELECTRICAL EQUIPMENT FOR MEASUREMENT, CONTROL, AND LABORATORY USE –

Part 031: Safety requirements for hand-held and hand-manipulated probe assemblies for electrical test and measurement

FOREWORD

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This commented version (CMV) of the official standard IEC 61010-031:2022 edition 3.0 allows the user to identify the changes made to the previous IEC 61010-031:2015+AMD1:2018 CSV edition 2.1. Furthermore, comments from IEC TC 66 experts are provided to explain the reasons of the most relevant changes, or to clarify any part of the content.

A vertical bar appears in the margin wherever a change has been made. Additions are in green text, deletions are in strikethrough red text. Experts' comments are identified by a blue-background number. Mouse over a number to display a pop-up note with the comment.

This publication contains the CMV and the official standard. The full list of comments is available at the end of the CMV.

IEC 61010-031 has been prepared by IEC technical committee 66: Safety of measuring, control and laboratory equipment. It is an International Standard.

It has the status of a group safety publication in accordance with IEC Guide 104.

This third edition cancels and replaces the second edition published in 2015, and Amendment 1:2018. IEC 61010-031 is a stand-alone standard.

This edition includes the following significant technical changes with respect to the previous edition:

- a) the scope has been made succinct. General information from the scope of Edition 2 has been moved to a new Clause 4. Consequently, Clause 4 to Clause 8 of Edition 2 have been renumbered. Clause 9 of Edition 2 has been deleted;
- b) in Clause 2, normative references have been dated and new normative references have been added;
- c) in 3.1.4, the definition of PROBE TIP has been modified;
- d) in 4.1, there is no longer any differentiation between high voltage and low voltage probe assemblies. Type C probe assemblies have been merged with Type B probe assemblies;
- e) in 4.1 d) "Kelvin" probes have been added to the list of probe assemblies as a new Type E and a new Figure 5;
- f) in 4.1 e), probes for voltage measurement without electrical connection to conductors have been added to the list of probe assemblies as a new Type F and a new Figure 6;
- g) in 4.2.1, spread of fire is no longer considered as a HAZARD;
- h) Subclause 4.4.2.5 from Edition 2 has been deleted;
- i) Subclause 4.4.4.3 from Edition 2 has been deleted;
- j) in 5.4.4.1 consideration has been given to SPACINGS and impedance;
- k) in 6.1.1, removable parts of PROBE TIPS which bear markings are allowed;
- l) in 6.1.5, the voltage to be marked for MEASUREMENT CATEGORIES is the AC line-to-neutral or DC voltage;
- m) in 7.4.2, requirements for unmated CONNECTORS have been modified as follows:
 - 1) Table 2 has been modified and expanded,
 - 2) a calculation method for CLEARANCES of CONNECTORS above 20 kV has been defined,
 - 3) CREEPAGE DISTANCES have been aligned with CLEARANCES;
- n) in 7.4.3.1 and 7.4.3.5, requirements for IP2X PROBE TIPS with retractable sleeve have been added;
- o) in 7.4.3.2, PROBE TIPS are now applicable to non-contact probe assemblies;
- p) in 7.5.2.3.2, the values of Table 5 have been modified;
- q) in 7.6.2, voltage tests of CLEARANCES are done without humidity preconditioning;
- r) pre-treatments for rigidity test from Clause 10 of Edition 2 have been moved to 9.2;
- s) Subclause 11.1 of Edition 2 has been deleted;
- t) addition of an exception for Type E probe assembly in 13.2. Removable parts of PROBE TIPS which bear markings are allowed;
- u) Figure F.1 has been modified;
- v) Annex G has been added, for determination of CLEARANCES for Table 2;
- w) Annex H has been added, covering line-to-neutral voltages for common mains supply systems.

The text of this International Standard is based on the following documents:

Draft	Report on voting
66/770/FDIS	66/771/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/publications.

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In this document the following print types are used:

- requirements and definitions: in roman type;
- NOTES and EXAMPLES: in smaller roman type;
- *conformity and tests: in italic type;*
- terms used throughout this document which have been defined in Clause 3: SMALL ROMAN CAPITALS.

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